

<b>Notice of References Cited</b>	Application/Control No. 10/671,254		Applicant(s)/Patent Under Reexamination OKAMOTO ET AL.	
	Examiner PAWANDEEP S. DHINGRA		Art Unit 2625	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,523,859 A	06-1996	Nakajima et al.	358/444
*	B	US-5,825,988 A	10-1998	Collard et al.	358/1.13
*	C	US-2001/0000360 A1	04-2001	Shibata, Koichi	713/202
*	D	US-6,285,459 B1	09-2001	Koakutsu et al.	358/1.15
*	E	US-2001/0025343 A1	09-2001	Chrisop et al.	713/193
*	F	US-2002/0032703 A1	03-2002	Gassho et al.	707/527
*	G	US-6,559,967 B1	05-2003	Akiba et al.	358/1.16
*	H	US-6,639,687 B1	10-2003	Neilsen, Robert Curt	358/1.14
*	I	US-2004/0012812 A1	01-2004	Shimizu, Yukihiko	358/1.15
*	J	US-6,745,334 B1	06-2004	Ikegami, Hideyuki	726/19
*	K	US-7,019,852 B2	03-2006	Morikawa, Takeshi	358/1.13
*	L	US-7,170,622 B2	01-2007	Nobuhara et al.	358/1.15
*	M	US-7,230,731 B2	06-2007	Dan et al.	358/1.14

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP 09-284572	10-1997	Japan	Inpue Rieko	H04N 1/44
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.